

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application

Inventor(s): Christopher J. Barbazette, et al.

Application No.:

10/618,313 4770

Confirm. No.:

July 10, 2003

Title:

Data Collection and Diagnostic System for a Semiconductor

Fabrication Facility

PATENT APPLICATION

Art Unit: 2121

Examiner: Chang, Sunray

CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited in the United States
Postal Service with sufficient postage as first class mail in an envelope addressed to, Non-Fee
Amendment Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on
September 10, 2007.

Michael L. Gencarella, Reg. No. 44,703 Signature Date: September 10, 2007

AMENDMENT

Mail Stop: Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to Office Action mailed on July 10, 2007. Please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 5 of this paper.

09/18/2007 HMARZI1 00000078 500805 19618313 02 FC:1251 128.00 DA